

L Number	Hits	Search Text	DB	Time stamp
1	33	(synthesiz\$3 synthesis) same (false near6 path)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/24 19:48
-	4131	((714/724,726,727,729).ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:15
-	644	((714/724,726,727,729).ccls.) and (boundary near2 scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:24
-	11	((714/724,726,727,729).ccls.) and (boundary near2 scan)) and delay near4 chain	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:24
-	21	((714/724,726,727,729).ccls.) and (boundary near2 scan)) and (delay near4 (chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:36
-	366	((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:35
-	12	((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))) and (delay near4 (chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:33
-	0	((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))) and (delay near4 (chain measurement))) not (((714/724,726,727,729).ccls.) and (boundary near2 scan)) and (delay near4 (chain measurement)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:26
-	9	((714/724,726,727,729).ccls.) and (boundary near2 scan)) and (delay near4 (chain measurement))) not (((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))) and (delay near4 (chain measurement)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:27
-	286	((714/724,726,727,729).ccls.) and (boundary near2 scan near4 (cell device buffer))) and (bypass multiplex\$2 MUX)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:33
-	109	((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 12:35
-	177	((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:36
-	7	((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))) and (delay near4 (chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:37

-	12	((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))) and (delay near4 (chain measur\$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/24 15:01
-	5	((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))) and (delay near4 (chain measur\$5))) not (((714/724,726,727,729).ccls.) and ((boundary near2 scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))) and (delay near4 (chain measurement)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:18
-	0	5710779.pn	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:19
-	2	US-5710779\$.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 14:11
-	1		USPAT; US-PGPUB	2004/07/23 13:21
-	1		USPAT; US-PGPUB	2004/07/23 13:22
-	1		USPAT; US-PGPUB	2004/07/23 13:22
-	1		USPAT; US-PGPUB	2004/07/23 13:23
-	1		USPAT; US-PGPUB	2004/07/23 13:24
-	1		USPAT; US-PGPUB	2004/07/23 13:24
-	1		USPAT; US-PGPUB	2004/07/23 13:27
-	304	((714/724,726,727,729).ccls.) and ((scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/24 15:00
-	17	((714/724,726,727,729).ccls.) and ((scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))) and (delay near4 (chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:48
-	202	((714/724,726,727,729).ccls.) and ((scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))) and (TAP JTAG "1149" "test access port")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:48
-	32	((714/724,726,727,729).ccls.) and ((scan near4 (cell device buffer)) same (bypass multiplex\$2 mux))) and (TAP JTAG "1149" "test access port")) and (delay near4 (test chain measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 13:49
-	1	\$-0994361\$.did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/23 14:12
-	59	(boundary near2 scan) same (delay near4 (test\$3 fault))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/24 15:02



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*Rajski, J.; Tamarapalli, N.; Tyszer, J.;*

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on , Volume: 19 , Issue: 10 , Oct. 2000  
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*Bhatia, S.; Jha, N.J.;*  
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[\[Abstract\]](#)   [\[PDF Full-Text \(1712 KB\)\]](#)   **IEEE JNL**

- ### 3 Scan-based transition test

**Savir, J.; Patil, S.;**  
**Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction**  
**on , Volume: 12 , Issue: 8 , Aug. 1993**  
**Pages:1232 - 1241**

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- #### 4 Delay-fault test generation and synthesis for testability under a static scan design methodology

Cheng, K.-T.; Devadas, S.; Keutzer, K.;  
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Pages:1217 - 1231

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*Yim, Y.T.; Kang, Y.S.; Kang, S.;*

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[\[Abstract\]](#) [\[PDF Full-Text \(636 KB\)\]](#) IEEE JNL

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**6 A new IEEE 1149.1 boundary scan design for the detection of delay defects**

*Sungju Park; Taehyung Kim;*

Design, Automation and Test in Europe Conference and Exhibition 2000. Proceedings , 27-30 March 2000

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**9 At-speed testing of delay faults for Motorola's MPC7400, a PowerPC microprocessor**

*Tendolkar, N.; Molyneaux, R.; Pyron, C.; Raina, R.;*

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